

The Amray Model 3600 LEAP (Low Energy Advanced Performance) can propel your field emission SEM performance beyond current boundaries to a new standard of excellence. The Amray 3600 LEAP delivers: □ high resolution – 4nm at 1kV, 1.5nm at 15kV □ optimized geometry for a short working distance at high tilts

with large samples (6mm w.d. at 45° tilt) iii high kV (25kV) for uncompromised analytical capabilities 

highly reliable patented Schottky field emission gun 

2048 x 2048 frame buffer for advanced digital imaging two 17", high resolution, 1000 line viewing

monitors 

5 axes motor-



ized eucentric stage \_ motorized 8" linear load lock for rapid sample exchange 

embedded computer control for all SEM functions

The Amray 3600 LEAP provides resolution that's out of this world - call 1-800-225-1462 for complete information on the Model 3600 LEAP and other Amray systems.



160 Middlesex Tpke., Bedford, MA 01730 Tel: 617-275-1400 Fax: 617-275-0740



## Sights Unseen.

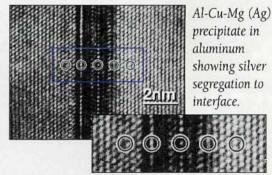
## With the New JEM-2010F **Field Emission** Electron Microscope You'll See It ... If It's There.

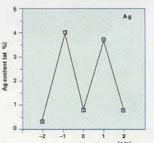
From JEOL...the newest generation of precision equipment that permits unprecedented resolution in 3-dimensional, subnanometer analysis of microstructures.

Featuring user-friendly operation and long-term stability, the JEM-2010F also offers:

- Schottky Emission: High Current High Brightness
- High Probe Current: 0.5nm Probe with 100 pA Current
- High Resolution: Information Limit 1.4Å, Scherzer 1.9Å
- Holography: Option Available
- STEM Resolution: 0.2nm Magnification: 8MX

Discover the JEM-2010F and visit sights previously unseen.





Data courtesy of Dr. James M. Howe, Department of Materials Science & Engineering, University of Virginia, U.S.A.



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